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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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TECHNOLOGY CENTER 2800  
OCT 17 2002

In re application of: Shing M. Lee

Attorney Docket No.: KLA1P012/P647US

Application No.: 09/695,726

Examiner: Fernandez, K.

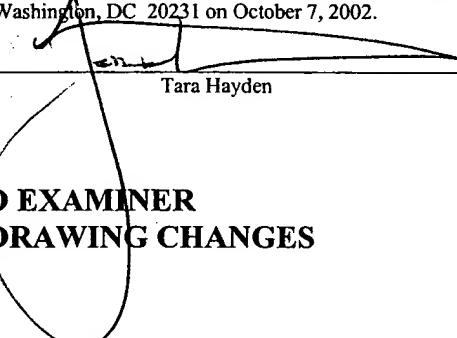
Filed: October 23, 2000

Group: 2881

Title: FILM THICKNESS MEASUREMENT  
USING ELECTRON-BEAM INDUCED  
X-RAY MICROANALYSIS

## CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail to: Commissioner for Patents, Washington, DC 20231 on October 7, 2002.

Signed: 

Tara Hayden

**SEPARATE LETTER TO EXAMINER  
REQUESTING APPROVAL OF DRAWING CHANGES**

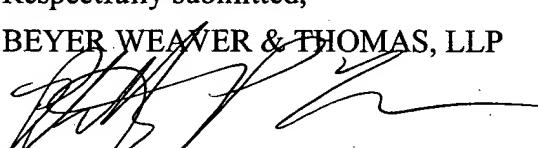
Commissioner for Patents  
Washington, D.C. 20231

Dear Sir:

Applicant proposes to amend the original drawings as indicated in red (or highlighted) in the enclosed photocopies. The approval of the Examiner is hereby requested. If there are any questions concerning this matter, please call the undersigned at the telephone number below.

Respectfully submitted,

BEYER WEAVER & THOMAS, LLP

  
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